




<p>Search Notes</p> 	<p>Application/Control No.</p> <p>10695864</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>UESAKA ET AL.</p>
	<p>Examiner</p> <p>Al-Nazer, Leith A</p>	<p>Art Unit</p> <p>2821</p>

Notes	Date	Examiner
Updated EAST prior art text search (see "Examiner Search Notes")	06/01/2006	Leith Al-Nazer
EAST interference text search (see "Examiner Search Notes")	06/01/2006	Leith Al-Nazer
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<p style="text-align: center;">Searched</p> 	<p>Application/Control No.</p> <p>10695864</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>UESAKA ET AL.</p>
	<p>Examiner</p> <p>Al-Nazer, Leith A</p>	<p>Art Unit</p> <p>2821</p>

Class	SubClass	Date	Examiner
343	703, 742, 832, 867	06/01/2006	Leith Al-Nazer

U.S. Patent and Trademark Office	Part of Paper No.: 20060601
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<i>Interference Searched</i> 	Application/Control No. 10695864	Applicant(s)/Patent Under Reexamination UESAKA ET AL.
	Examiner Al-Nazer, Leith A	Art Unit 2821

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